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SYNOPSIS

	Number and Title of the Indian Standard	IS 17182 : 2020 X-ray Diffraction Based Residual Stress Measurement.
a)	Scope	This standard prescribes the procedure to be followed for measuring residual stresses present on surfaces of polycrystalline metallic components by using X-ray diffraction (XRD) technique. This procedure is intended for use along with the procedures mentioned in manuals provided by the manufacturers of X-ray diffraction systems.
b)	Salient features of content	This Standard includes Principal of Test, Terminology, Measurement Principal, X-Ray Diffraction Based residual Stress Measurement System, Test Procedure, Acceptance Standard and Reporting of Test Results.
c)	Type/Grade/Class if any, covered in Indian Standard Specification	-
d)	Disclaimer	-